



PATENT
455610-2590.2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Martin MILLER et al.

Serial No. : 10/673,735

Filed : September 29, 2003

Title : METHOD OF ANALYZING SERIAL DATA STREAMS

Art Unit : 2133

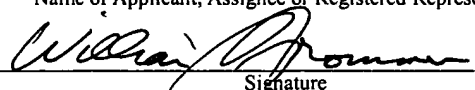
Examiner : To Be Assigned

745 Fifth Avenue
New York, NY 10151

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on December 3, 2004.

William S. Frommer, Reg. No. 25,506

Name of Applicant, Assignee or Registered Representative



Signature

December 3, 2004

Date of Signature

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir

In compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, Applicants are filing this Supplemental Information Disclosure Statement, the accompanying form PTO-1449 and the documents noted thereon.

So far as Applicants are aware, this Supplemental Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits.

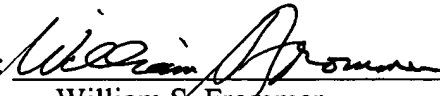
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The filing of this Information Disclosure Statement is not an admission that the documents identified herein constitute prior art to the present application.

It is believed that no fees are required by the instant submission as it is prior to receipt of the first Office Action in this application. However, if any fees are required, or if any overpayment has been made, please charge Deposit Acct. No. 50-0320.

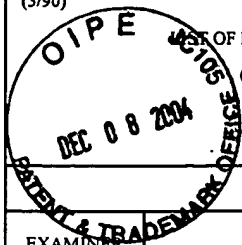
Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
Attorney for Applicants

By: 
William S. Frommer
Reg. No. 25,506
(212) 588-0800

Encs. - PTO Form 1449

Based on Form PTO-1449
(3/90)



LIST OF REFERENCES CITED BY APPLICANT

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| | AM | 4,694,244 | 08/15/87 | Whiteside et al | | | |

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| | AN | JP4105070 | 04/07/92 | Japan | | | Abstract | |
| | AO | JP5196641 | 08/06/93 | Japan | | | Abstract | |
| | AP | JP5264595 | 10/12/93 | Japan | | | Abstract | |
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| | AR | JP9005362 | 01/10/97 | Japan | | | Abstract | |
| | AS | JP10163859 | 06/19/98 | Japan | | | Abstract | |
| | AT | JP11098876 | 04/09/99 | Japan | | | Abstract | |
| | AU | JP62003544 | 01/09/87 | Japan | | | Abstract | |
| | AV | EP 0 631 143 | 12/28/94 | Europe | | | | |
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| | AY | | Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 rd Edition, McGraw-Hill, New York, 1997, pp 229-249 |
| | AZ | | <i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996 |
| | BA | | HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999 |
| | BB | | Infinium DCA, Agilent Technologies, March 7, 2002 |
| | BC | | Communication waveform measurements, Hewlett Packard, June 26, 1996 |

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| | BJ | Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994 |
| | BK | R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999 |
| | BL | Technology Standards, Tektronix Website (www.tek.com/M Measurement/Solutions/tech_standards/index.html?wt=257) |
| | BM | Communications Signal Analyzer, Tektronix Website (www.tektronix.com/optical) |
| | BN | RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website (www.Tektronix.com/accessories) |
| | BO | Design of FIR Filters by Windowing, MIT Website, (http://web.mit.edu/6.555/www/fir.html) |
| | BP | A New Digital PLL at the Technische Universitaet Berlin, Technische Universitaet Berlin Website (www.tdl.com/gottsch/tuberlin.htm) |
| | BQ | Low Jitter Digital PLL – ZL30407, Zalink Semiconductor Website, (http://products.zarlink.com/product_portlets/new_timer.htm) |
| | BR | Michael K. Williams, et al., A Discussion of Methods for Measuring Low-Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-652 |
| | BS | Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000 |
| | BT | Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002 |
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| | BV | Andy Baldman, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002 |
| | BW | University of New Hampshire Technical Document, "fast Ethernet" February 13, 2003 |

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| | BA | | HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999 |
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| | BK | R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999 |
| | BL | Technology Standards, Tektronix Website (www.tek.com/M Measurement/Solutions/tech_standards/index.html?wt=257) |
| | BM | Communications Signal Analyzer, Tektronix Website (www.tektronix.com/optical) |
| | BN | RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website (www.Tektronix.com/accessories) |
| | BO | Design of FIR Filters by Windowing, MIT Website, (http://web.mit.edu/6.555/www/fir.html) |
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